

Notice of References Cited	Application/Control No. 10/057,745	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6479369 B1	11-2002	Miyoshi	438/435
	B	US-6403429 B2	06-2002	Noble	438/294
	C	US-6339004 B1	01-2002	Kim	438/296
	D	US-6306712 B1	10-2001	Rodder et al.	438/289
	E	US-6184091 B1	02-2001	Gruening et al.	438/270
	F	US-6146970	11-2000	Witek et al.	438/424
	G	US-5246877	09-1993	Hisamoto et al.	438/295
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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